

## PATENT ABSTRACTS OF JAPAN

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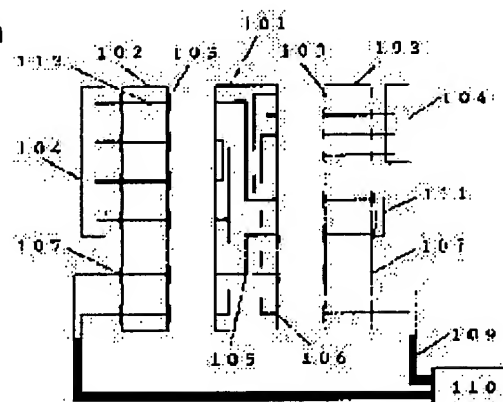
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(54) METHOD FOR INSPECTING CIRCUIT BOARD, INSPECTING BOARD, AND CIRCUIT BOARD INSPECTING DEVICE

(57)Abstract:

PURPOSE: To obtain a simple method for inspecting high-density circuit board.

CONSTITUTION: Inspecting substrates 102 respectively provided with probe terminals 103 corresponding to lands 106 to be measured on a circuit board 101 to be inspected on one surfaces and parts 104 and 111 or parts having functions equivalent to those of the parts 104 and 111 on the other surfaces, an inspecting signal generating device 110 which inspects connected relations by actuating the parts 104 and 111, and a means which brings probe terminals 103 on the substrates 102 into contact with corresponding terminals of the circuit board 101 to be inspected are provided.



## LEGAL STATUS

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